

BUK7619-100B

N-channel TrenchMOS standard level FET Rev. 01 — 10 October 2007

Product data sheet

Product profile

1.1 General description

N-channel enhancement mode power Field-Effect Transistor (FET) in a plastic package using NXP High Performance Automotive (HPA) TrenchMOS technology.

1.2 Features

- TrenchMOS technology
- 175 °C rated

- Q101 compliant
- Standard level compatible

1.3 Applications

- Automotive systems
- Motors, lamps and solenoids
- General purpose power switching
- 12 V, 24 V and 42 V loads.

1.4 Quick reference data

- \blacksquare E_{DS(AL)S} \leq 222 mJ
- $I_D \le 64 A$

- \blacksquare R_{DSon} = 17 mΩ (typ)
- Arr P_{tot} \leq 200 W

Pinning information

Table 1. **Pinning**

Pin	Description	Simplified outline	Symbol
1	gate (G)		
2	drain (D)	mb	D
3	source (S)		
mb	mounting base; connected to drain (D)		mbb076 S
		SOT404 (D2PAK)	



2 of 12

N-channel TrenchMOS standard level FET

3. Ordering information

Table 2. Ordering information

Type number	Package		
	Name	Description	Version
BUK7619-100B	D2PAK	plastic single-ended surface-mounted package (D2PAK); 3-leads (one lead cropped)	SOT404

4. Limiting values

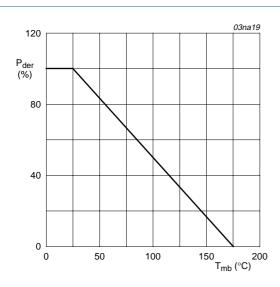
Table 3. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage		-	100	V
V_{DGR}	drain-gate voltage (DC)	$R_{GS} = 20 \text{ k}\Omega$	-	100	V
V_{GS}	gate-source voltage		-	±20	V
I _D	drain current	$T_{sp} = 25 ^{\circ}\text{C}$; $V_{GS} = 10 \text{V}$; see Figure 2 and 3	-	64	Α
		$T_{sp} = 100 ^{\circ}\text{C}; V_{GS} = 10 \text{V}; \text{see} \frac{\text{Figure 2}}{}$	-	45	Α
I _{DM}	peak drain current	T_{mb} = 25 °C; pulsed; $t_p \le 10 \mu s$; see Figure 3	-	256	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 1</u>	-	200	W
T _{stg}	storage temperature		-55	+175	°C
Tj	junction temperature		-55	+175	°C
Source-c	Irain diode				
I _{DR}	reverse drain current	T _{mb} = 25 °C	-	64	Α
I _{DRM}	peak reverse drain current	T_{mb} = 25 °C; pulsed; $t_p \le 10 \mu s$	-	256	Α
Avalanch	ne ruggedness				
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	unclamped inductive load; I_D = 64 A; $V_{DS} \le 100$ V; R_{GS} = 50 Ω ; V_{GS} = 10 V; starting at T_j = 25 °C	-	222	mJ
E _{DS(AL)R}	repetitive drain-source avalanche energy		[1] -	-	mJ

[1] Conditions:

- a) Maximum value not quoted. Repetitive rating defined in Figure 16.
- b) Single-pulse avalanche rating limited by $T_{j(max)}$ of 175 $^{\circ}\text{C}.$
- c) Repetitive avalanche rating limited by an average junction temperature of 170 $^{\circ}\text{C}.$
- d) Refer to application note AN10273 for further information.



$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100 \%$$

Fig 1. Normalized total power dissipation as a function of mounting base temperature

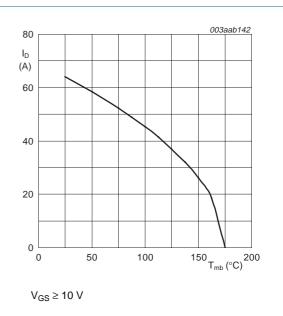
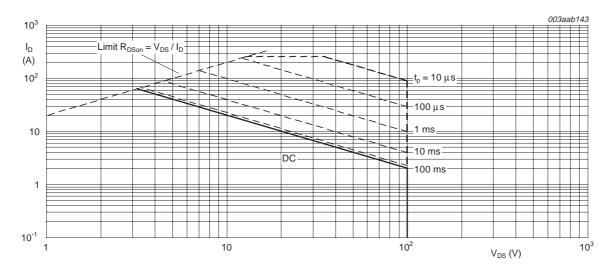


Fig 2. Continuous drain current as a function of mounting base temperature



 $T_{mb} = 25$ °C; I_{DM} is single pulse.

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

5. Thermal characteristics

Table 4. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base		-	-	0.74	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient	mounted on a printed-circuit board; minimum footprint	-	50	-	K/W

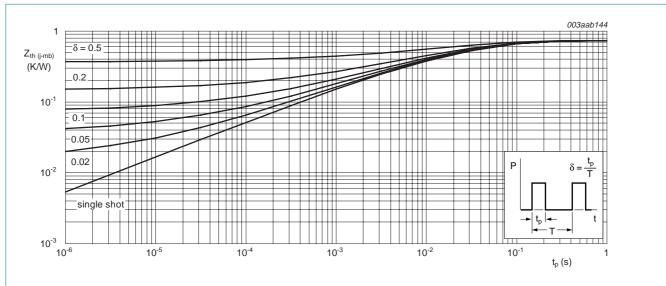


Fig 4. Transient thermal impedance from junction to mounting base as a function of pulse duration

6. Characteristics

Table 5. Characteristics

 $T_j = 25 \,^{\circ}C$ unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V$				
		T _j = 25 °C	100	-	-	V
		$T_j = -55 ^{\circ}\text{C}$	89	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; see <u>Figure 9</u> and <u>10</u>				
		T _j = 25 °C	2	3	4	V
		T _j = 175 °C	1	-	-	V
		T _j = −55 °C	-	-	4.4	V
I _{DSS}	drain leakage current	$V_{DS} = 100 \text{ V}; V_{GS} = 0 \text{ V}$				
		T _j = 25 °C	-	0.02	1	μΑ
		T _j = 175 °C	-	-	500	μΑ
I_{GSS}	gate leakage current	$V_{GS} = \pm 20 \text{ V}; V_{DS} = 0 \text{ V}$	-	2	100	nΑ
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; \text{ see } \frac{\text{Figure 7}}{2} \text{ and } \frac{8}{2}$				
		T _j = 25 °C	-	17	19	$m\Omega$
		T _j = 175 °C	-	-	49	$m\Omega$
Dynamic	characteristics					
Q _{G(tot)}	total gate charge	$I_D = 25 \text{ A}; V_{DD} = 80 \text{ V}; V_{GS} = 10 \text{ V};$ see Figure 14	-	53	-	nC
Q_{GS}	gate-source charge		-	11	-	nC
Q_{GD}	gate-drain charge		-	27	-	nC
C _{iss}	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$	-	2555	3400	pF
C _{oss}	output capacitance	see Figure 12	-	340	480	рF
C _{rss}	reverse transfer capacitance		-	84	115	рF
t _{d(on)}	turn-on delay time	$V_{DS} = 30 \text{ V}; R_L = 1.2 \Omega;$	-	19	-	ns
t _r	rise time	V_{GS} = 10 V; R_G = 10 Ω	-	45	-	ns
t _{d(off)}	turn-off delay time		-	85	-	ns
t _f	fall time		-	34	-	ns
Source-d	rain diode					
V_{SD}	source-drain voltage	$I_S = 25 \text{ A}$; $V_{GS} = 0 \text{ V}$; see Figure 15	-	0.85	1.2	V
t _{rr}	reverse recovery time	$I_S = 20 \text{ A}$; $dI_S/dt = -100 \text{ A/}\mu\text{s}$;	-	116	-	ns
Q _r	recovered charge	$V_{GS} = 0 \text{ V}; V_{R} = 30 \text{ V}$	-	130	-	nC

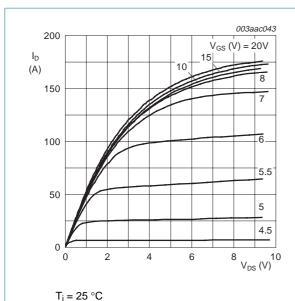
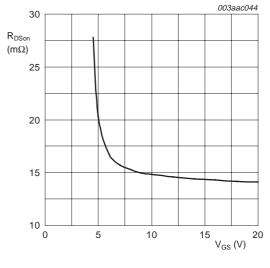


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values



 $T_i = 25 \,^{\circ}C; I_D = 10 \,^{\circ}A$

Fig 6. Drain-source on-state resistance as a function of gate-source voltage; typical values

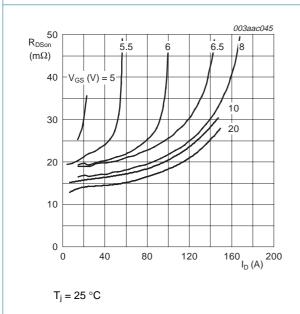
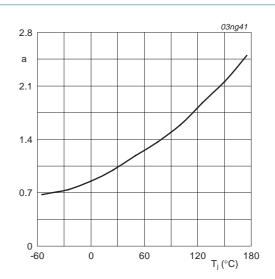
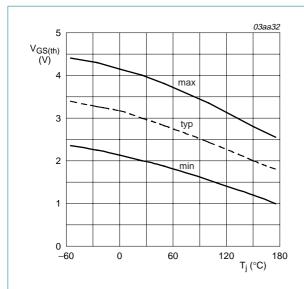


Fig 7. Drain-source on-state resistance as a function of drain current; typical values



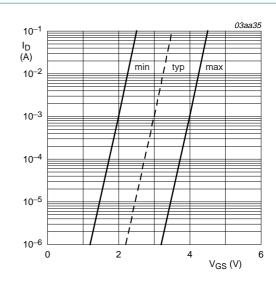
$$a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$$

Fig 8. Normalized drain-source on-state resistance factor as a function of junction temperature



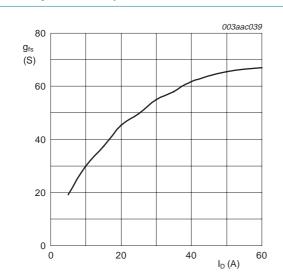
 $I_D = 1 \text{ mA}; V_{DS} = V_{GS}$

Fig 9. Gate-source threshold voltage as a function of junction temperature



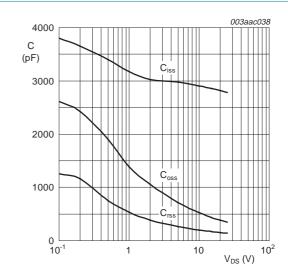
 $T_i = 25 \,^{\circ}C; V_{DS} = V_{GS}$

Fig 10. Sub-threshold drain current as a function of gate-source voltage



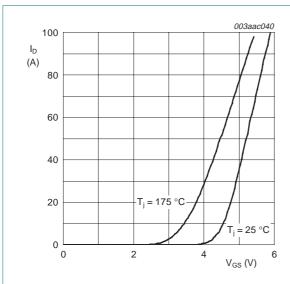
 $T_i = 25 \,^{\circ}C; \, V_{DS} = 25 \,^{\circ}V$

Fig 11. Forward transconductance as a function of drain current; typical values



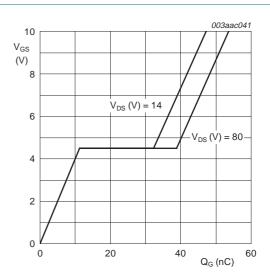
 $V_{GS} = 0 V; f = 1 MHz$

Fig 12. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values



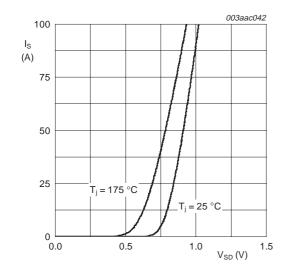
 $V_{DS} = 25 \text{ V}$

Fig 13. Transfer characteristics: drain current as a function of gate-source voltage; typical values



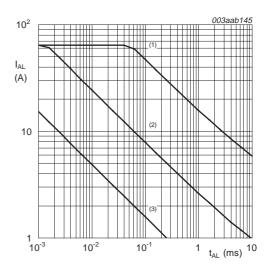
 $T_i = 25 \,^{\circ}C; I_D = 25 \,^{\circ}A$

Fig 14. Gate-source voltage as a function of gate charge; typical values



 $V_{GS} = 0 V$

Fig 15. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values



See Table note 1 of Table 3 Limiting values.

- (1) Single-pulse; T_i = 25 °C.
- (2) Single-pulse; T_i = 125 °C.
- (3) Repetitive.

Fig 16. Single-pulse and repetitive avalanche rating; avalanche current as a function of avalanche time

7. Package outline

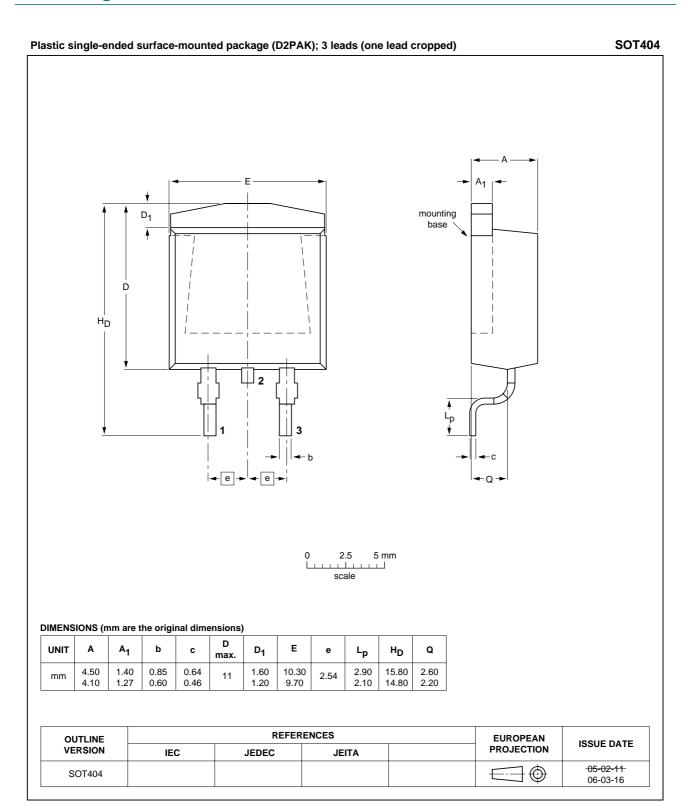
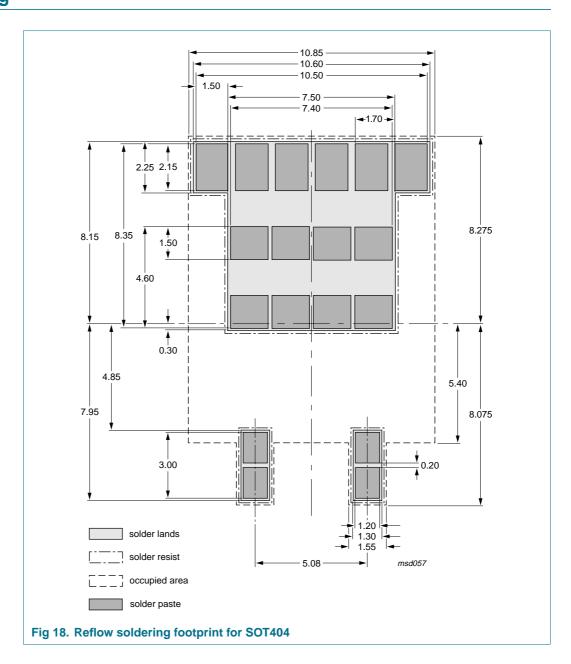


Fig 17. Package outline SOT404 (D2PAK)

8. Soldering



9. Revision history

Table 6. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BUK7619-100B_1	20071010	Product data sheet	-	-

10. Legal information

10.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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BUK7619-100B

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12. Contents

1	Product profile	1
1.1	General description	1
1.2	Features	1
1.3	Applications	1
1.4	Quick reference data	1
2	Pinning information	1
3	Ordering information	2
4	Limiting values	2
5	Thermal characteristics	4
6	Characteristics	5
7	Package outline	ē
8	Soldering 1	IC
9	Revision history 1	IC
10	Legal information 1	11
10.1	Data sheet status	11
10.2	Definitions	11
10.3	Disclaimers	11
10.4	Trademarks1	11
11	Contact information 1	11
12	Contents	12

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